

<b>Notice of References Cited</b>	Application/Control No. 09/683,002	Applicant(s)/Patent Under Reexamination BASTIAENS ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

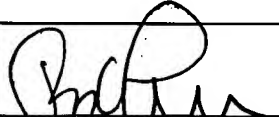
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	B	US-			
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	E	US-			
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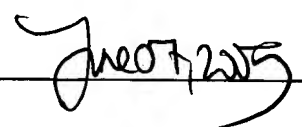
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Examiner

Rip A. Le

Art Unit

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Page 1 of 2

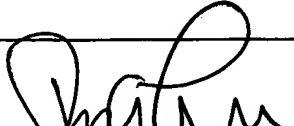
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	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

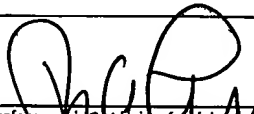
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